NASA TECHNICAL MEMORANDUM



CASETILE

ELECTRICAL PERFORMANCE OF THREE SOLAR THERMOELECTRIC TEST SECTIONS

by William J. Bifano, Erich W. Kroeger, and Robert B. Ruch

Lewis Research Center Cleveland, Obio 44135



THE RESERVE OF THE PROPERTY OF								
1. Report No. NASA TM X-2175	2. Government Access	ion No.	3. Recipient's Catalog	No.				
4. Title and Subtitle ELECTRICAL PERFORMANCE	OF THREE SOL	AR THERMO-	5. Report Date February 197	1				
ELECTRIC TEST SECTIONS			6. Performing Organiza	ation Code				
7. Author(s) William J. Bifano, Erich W. K	roeger, and Robe		8. Performing Organiza E-5925	ition Report No.				
9. Performing Organization Name and Address			10. Work Unit No. 120–27					
Lewis Research Center		<u> -</u> -	120-21	Na				
National Aeronautics and Space	Administration		11. Contract or Grant	IVO.				
Cleveland, Ohio 44135		h	13. Type of Report an	d Period Covered				
12. Sponsoring Agency Name and Address			Technical Me	750				
National Aeronautics and Space	Administration	<u> -</u>	14. Sponsoring Agency					
Washington, D.C. 20546			The Openioring Tigeney					
15. Supplementary Notes		-						
10. Abstract								
Current-voltage characteristics electric generator designed to a nine silicon-germanium thermore Measurements were made at available three test sections produced junction temperatures approxing power because of poor thermal One of the tests sections, life-of about 14 percent, correspondent	operate at 0.25 A occuples mechanic erage hot junction of the design power nately 50°C high contact between tested for 3000 ho	U from the sun. Excally attached to a ken temperatures in the routput of 2.8 watther than predicted we the thermocouple stours, exhibited an in	ach test section peryllium radiate the range of 640° s at 1.0 volt; however required to a total and the radiate the case in internal and the case in	consisted of or plate. I to 940° C. wever, achieve this tor plate. nal resistance				
17. Key Words (Suggested by Author(s))		18. Distribution Statement						
Thermoelectric power generati	on	Unclassified - unlimited						
Thermoelectricity								
Thermoelectric generators								
Solar generators								
19. Security Classif. (of this report)	20. Security Classif. (c	of this page)	21. No. of Pages	22. Price*				
Unclassified	Unclassi	ssified 25 \$						

 $^{^{*}}$ For sale by the National Technical Information Service, Springfield, Virginia $\,$ 22151

ELECTRICAL PERFORMANCE OF THREE SOLAR

THERMOELECTRIC TEST SECTIONS

by William J. Bifano, Erich W. Kroeger, and Robert B. Ruch

Lewis Research Center

SUMMARY

Three test sections of a solar thermoelectric generator, designed for minimum specific weight at 0.25 AU from the sun, were electrically tested. Each test section consisted of nine silicon-germanium thermocouples mechanically attached to a beryllium radiator plate. Measurements were made at average hot junction temperatures in the range of 640° to 940° C.

The electrical characteristics of the three test sections were essentially identical, each producing a design power output of 2.8 watts at 1.0 volt. However, hot and cold junction temperatures approximately 50° C higher than predicted were required to achieve this power because of poor thermal contact between the thermocouple stud and the radiator plate. One test section, life-tested for 3000 hours, exhibited an increase in internal resistance of 14 percent, corresponding to a decrease in power output of about 6 percent.

INTRODUCTION

For solar probe applications, a study (ref. 1) has shown that silicon solar cells could provide nearly constant electrical power from 1 AU to on the order of 0.25 AU (an astronomical unit, AU, is defined as the mean-earth-sun distance). However, for closer distances, thermal control problems are anticipated which may require the use of an alternate power system such as a solar thermoelectric (TE) flat-plate generator. The thermoelectric generator would have a much higher temperature capability than solar cells; could be designed to operate normal to the sun's ray at 0.25 AU; and, with tilting used to provide thermal flux control, would provide constant power to distances of 0.1 AU or less. Hence, for continuous electrical power generation from earth to a

near-sun design point, a hybrid system could be used, that is, solar cells between Earth and the distance from the sun where solar-cell temperature limits are reached and a solar TE flat-plate generator for closer distances.

Under contract NAS 3-10600, the RCA Corporation, Harrison, New Jersey, designed a 150-watt solar flat-plate thermoelectric generator for minimum specific weight, based on a design point of 0.25 AU (ref. 2). In order to demonstrate the feasibility of the concept, three test sections of the generator were fabricated (ref. 3), instrumented, and delivered to Lewis for testing. The pertinent results of the generator design study are presented here for completeness.

	
Number of thermocouples	480
Current, A	5. 63
Voltage, V	26.6
Power, W	150
Efficiency, percent	3.57
Weight, kg (lb)	6 (13. 2)
Area, m ² (ft ²)	0.383 (4.12)
Specific weight, kg/m ² (lb/ft ²)	15. 8 (3. 23)
Power/area, W/m ² (W/ft ²)	382 (36. 4)
Power/weight, W/kg (W/lb)	24.8 (11.3)
Hot junction temperature, ^O C (^O F)	790 (1454)
Cold junction temperature, ^o C (^o F)	430 (806)
Design-point distance, AU	0, 25
The state of the s	1000 8

The current-voltage characteristics of the three test sections were measured and one test section was life-tested for 3000 hours. In addition, a nine-thermocouple prototype test section was life-tested for 5500 hours in a separate experiment. The tests were conducted to provide a first-order evaluation of the mechanical and electrical behavior of the test sections and to uncover areas in which further development might be required. The results of these tests are reported herein.

DESCRIPTION

Test Section

Each of the planar test sections consists of nine silicon-germanium (Si-Ge) thermocouples arranged in a 3-by-3 array and electrically connected in series. A test section is shown in figure 1 and a sketch of a Si-Ge thermocouple is shown in figure 2. The overall dimensions of the test section are 8.9 by 8.9 by 2.5 centimeter. Each individual Si-Ge thermocouple consists of a phosphorus-doped (n-type) and a boron-doped (p-type)

thermoelement metallurgically bonded to a heat receptor plate or 'hot shoe.' The Si-Ge alloy used is nominally 63.5-atomic-percent silicon while an 85-weight-percent silicon - 15-weight-percent molybdenum alloy is used for the hot shoe. The thermoelements are bonded through a cold stack to a beryllium mounting stud at the cold end. The cold stack consists of a tungsten shoe, a copper pedestal, a tungsten compensator, and a copper strap used as an electrical lead for each thermoelement. An alumina disk is included between the cold stack and the mounting stud to electrically isolate the thermocouple from the beryllium radiator plate. The thermocouples are mechanically fastened to the radiator plate, and the outer radiator plate surface is coated with calcium titanate to provide a high-emittance surface. Fibrous insulation (Johns-Manville Min-K 2002) is used between the thermocouples to minimize shunt heat loss. The insulation is machined in bulk and fitted into large areas. Small, irregular areas are filled with loose microquartz insulation.

It is important to note that although a selective solar absorptance coating was assumed in designing the generator, no such coating was provided on the hot shoes of the test sections. Hence, no attempt was made to duplicate the solar spectrum at 0.25 AU in heating the test sections.

Instrumentation

On each test section, five of the nine Si-Ge thermocouples were instrumented with Chromel-Alumel thermocouples at the cold end and tungsten - 3-percent-rhenium/tungsten - 25-percent-rhenium thermocouples on the hot shoes. The five Si-Ge thermocouples instrumented were located at the four corners and the center of the array. In addition, 10 Alumel voltage probes were provided (located on the copper connecting straps). Two copper straps were used, one at each end of the circuit, as power taps.

Test Fixture

The test fixture, shown in figure 3, consists of two infrared strip heaters, arranged so as to uniformly heat a 8.9- by 8.9-centimeter test area. Since each infrared lamp has an active length of 15 centimeters, two water-cooled copper masks were required, one at each end, to give the desired 8.9-centimeter dimension. For the initial performance mapping of the test sections, the fixture was fastened to the hemispherical end cap of a vacuum chamber having a liquid-nitrogen-cooled, blackened shroud. (The test section was supported in the test fixture by four spring-loaded pins mounted in an aluminum frame. The pins made point contact with the radiator plate edges.) A brass plate bolted to the chamber bulkhead was used for all electrical and coolant feedthroughs.

In the subsequent life-testing of one test section, a different vacuum system was used. In this system, the radiator viewed a conventional glass bell jar instead of the blackened shroud used in the performance tests. The effect on the operating temperatures of the test section was negligible.

TESTING PROCEDURE

Performance Mapping

Each test section was tested in the following manner: Room-temperature resistance of the entire nine-thermocouple string was measured both before and after installation in the vacuum chamber.

The test section was then connected in the load circuit, as shown schematically in figure 4. Two potentiometers, 0 to 2 ohms and 0 to 8 ohms, connected in parallel, were used as the variable resistance load and a 50-milliohm shunt was used to measure thermoelectric current.

After a vacuum pressure of 10⁻⁵ torr or less was reached, the heater power was turned on and was gradually increased to achieve operating conditions. Typically a heating rate of 25° C per minute was used. Because of uncertainties regarding the hot shoe temperature-sensing thermocouples (e.g., location, accuracy, behavior in test environment, and intimacy of contact with device), it was decided to use the output of the test section itself to define reference operating conditions. Hence, the test section was heated to temperatures which resulted in the predicted output voltage of 1 volt and current of 2.8 amperes with a load-to-internal-resistance ratio of about 1.2. Typically, an average hot junction temperature of about 840°C was required to achieve the reference design power. This is discussed in more detail later in the report. With the heater input power fixed, the current-voltage (I-V) characteristics were determined by varying the external load and allowing the test section to reach a steady-state condition (usually within 15 min) before recording the I-V point. Three such current-voltage points, in addition to an open-circuit voltage point, were recorded. The procedure was then repeated for average hot junction temperatures of 640°, 740°, and 940° C. These data are tabulated in appendix A. The resulting I-V characteristics of the three test sections are presented in figure 5.

Initially, the W-3Re/W-25Re thermocouples provided on five of the nine hot shoes by the vendor were used to determine the hot junction temperature. However, it was immediately obvious that the W-3Re/W-25Re thermocouple readings were not representative of true junction temperatures since the corresponding open-circuit voltages were higher than predicted for Si-Ge. As a result it was decided to use the output of the Si-Ge thermocouple itself as an indication of the hot junction temperature. A typical

hot side temperature distribution is shown in figure 6, where junction temperatures obtained from the Si-Ge output are compared to those indicated by the W-3Re/W-25Re thermocouples.

Life-Test Procedures

Test section 3 was arbitrarily selected for life testing. Again, the internal resistance was measured and the test section was heated to nominal reference design conditions. The test section was operated for 3000 hours. The data system was programmed to automatically record the load current and various temperatures and voltages every 12 hours. Internal resistance was measured periodically using the method outlined in appendix B.

There were six shutdowns during the 3000-hour test, caused by various system malfunctions. There were no indications that any of the shutdowns were due to the module itself. Also, there were three controlled shutdowns very early in the life-test to allow modification of auxiliary equipment.

TEST RESULTS

Performance Mapping

The resistance of the three test sections, as received, was found to be consistent with values quoted by the vendor, being 132, 124, and 119 milliohms at room temperature for test sections 1, 2, and 3, respectively. The resistance of the individual thermocouples, including representative bond-contact resistance, is presented in reference 3.

Comparison of the I-V characteristics of test sections 1, 2, and 3 (figs. 5(a), (b), and (c), respectively) indicates that the performance of all three sections is nearly identical. Based on the thermoelectric panel design analysis (ref. 2), the nine-thermocouple test sections are to produce 2.8 watts at 1 volt at a hot junction temperature of 791° C and a cold junction temperature of 430° C, resulting in a temperature difference across the element of 361° C. The temperatures actually required to achieve 2.8 watts at 1 volt are tabulated for each of the three test sections and compared to the reference design temperatures in table I. Note that while the measured output of 2.82 ± 0.07 watts at 1.0 ± 0.01 volts was obtained with a temperature difference of $361^{\circ}\pm5^{\circ}$ C, corresponding to the reference design, resultant hot and cold junction temperatures exceeded reference design temperatures by about 50° C. This is due primarily to poor thermal contact between the thermocouple stud and the radiator baseplate.

For test section 1, this poor thermal contact resulted in a measured cold-stack temperature difference ΔT_{CS} (between the cold junction and radiator surface) of 43° C compared to a calculated value of 15° C. Although no instrumentation was provided on the radiator surface of test sections 2 and 3, it is reasonable to assume a similar cold-stack ΔT existed for these test sections.

Techniques to improve the thermal contact between the stud and radiator, and thereby reduce ΔT_{CS} , have since been developed under another program (ref. 4). It has been established that a ΔT_{CS} of 15°C can be achieved by using a modified stud design which permits application of 10 to 15 inch-pounds (113 to 170 cm-N) of torque in tightening the mount nut to the stud. For the solar test sections the applied torque was limited to about 1 inch-pound (11.3 cm-N) since greater torques were found to cause breakage of the stud at the neck of the tapered region.

Another factor which might cause the measured junction temperatures to deviate from design values is the uncertainty regarding the emittance of the calcium titanate coating. It was found that an initial ''heat treatment'' of the coated radiator was required each time the test section was exposed to the atmosphere to stabilize the emittance of the surface (typically about 3 hr of operation at a radiator surface temperature of about 500°C). During this time, the radiator surface temperature was observed to decrease gradually for a fixed input power indicating a gradual increase in emittance of the calcium titanite. Since no direct emittance measurements were made, the ''stabilized'' value of emittance can only be assumed. If, for example, this value were 0.75 rather than the 0.85 used in the reference design analysis, the radiator temperature would increase by about 25°C. This, in addition to the cold-stack temperature drop, would account for the 50°C variation from design values in junction temperatures. Additional uncertainties regarding the thermal conductivity of the Johns-Manville Min-K 2002 thermal insulation and the importance of edge effects in testing small panels cannot be readily estimated; however, it appears that they are relatively minor.

Life-Test Results

As is generally known, Si-Ge thermocouples exhibit some degradation during the first 1500 hours of operation, the amount being dependent for the most part on the temperature range over which the thermoelements operate (ref. 5). Typically, this initial degradation is of the order of 5 percent. Following this 1500-hour "burn-in," the material is considered to be essentially stable, undergoing an additional 5 to 7 percent degradation during the next 20 000 to 30 000 hours of operation. Since solar panel test section 3 was subjected to several hundred hours of performance mapping prior to placing it on life-test, it was obvious that the degradation rates described above would not be observed. (Since the degradation mechanisms are time- and temperature-dependent

and are reversible, life-testing of an as-fabricated Si-Ge device would be required to observe the true degradation rates.)

Another complication was the behavior of the calcium titanate emittance coating on the radiator plate. As previously explained, the coating required a "heat treatment" each time it was exposed to atmosphere in order to obtain the desired emittance. Thus, after test section 3 was installed in the life-test fixture and heated to reference design power output, the cold junction temperatures were higher than anticipated. As shown in figure 7, this decrease in cold junction temperature due to the improving emittance occurred during the first 100 hours of operation. A corresponding variation in output power during this period is also shown in the same figure.

Because of the difficulties encountered in establishing life-test conditions, a number of adjustments in input power were made during the first 300 to 400 hours. However, as shown in figure 7, the performance of the test section was essentially stable from 400 to 3000 hours, during which time the input power was held constant and the output voltage of the test section was maintained at 1 volt. Actually, under the circumstances, the internal electrical resistance, presented as a function of time in figure 7, is more useful in characterizing the performance of the solar panel test section. Note, for example, that during the first 600 hours the internal resistance increased from 0.315 to 0.340 ohm, while during the remaining 2800 hours it increased from 0.340 to 0.360 ohm. This is in accordance with the predicted behavior of Si-Ge thermocouples (ref. 5), the increase in resistance being attributed to the precipitation of phosphorus dopant and subsequent diffusion to nucleation sites with an attendant loss of current carriers.

In a separate experiment, a nine-thermocouple prototype test section was life-tested for 5500 hours. A power degradation of about 8 percent was observed after 5500 hours operation with an attendant resistance increase of 18 percent. The details of this test are given in appendix B.

SUMMARY OF RESULTS

Performance testing of three uncoated solar thermoelectric test sections produced the following results:

- 1. The reference design output power of the test sections, 2.8 watts at 1 volt, was achieved at the design temperature difference of $361\pm5^{\circ}$ C; however, hot and cold junction temperatures approximately 50° C higher than predicted were required primarily because of poor thermal contact between the thermocouple stud and the radiator plate.
- 2. The electrical performance characteristics of the three test sections, as received, were essentially identical.
- 3. One test section, life-tested for 3000 hours at reference design conditions, exhibited an increase in internal electrical resistance of about 14 percent. Comparison of

life-test data from a similar module (see appendix B) indicates that a resistance increase of 14 percent is accompanied by a power decrease of about 6 percent.

4. Except for a selective solar absorber coating, the feasibility of the weight-optimized design of the solar thermoelectric converter has been demonstrated.

Lewis Research Center,
National Aeronautics and Space Administration,
Cleveland, Ohio, October 9, 1970,
120-27.

APPENDIX A

TABULATION OF DATA

Test Section 1

Parameter					Hot sho	e number				Aver
	32	52	17	45	31	48	38	46	49	age
Run 21-	1; curre	nt, 0; tot	al voltag	e, 2.219	V; total	power, 0			L	
Hot junction temperature (calc), T _{HJ} , ^o C	938. 5		936		941		944		950.5	942
Cold junction temperature (meas), T _{CJ} , C	483.5		513		492		517		508.5	503
Temperature difference, ΔT , ^{0}C	455		423		449		427		442	439
Radiator temperature (meas), TR, OC	443		474		432		467	0.0100	443	452
Voltage, V	0.2542	0. 2437	0. 2367	0, 2553	0. 2517	0, 2538	0. 2392	0. 2190	0, 2477	
Run 21-2; curre	nt, 2.01	A; total	voltage,	1. 492 V;	total pov	ver, 3.0	W	1	1	,
Hot junction temperature (calc), T _{HJ} , ^O C	928		934		934		939		941	935
Cold junction temperature (meas), T _{CJ} , °C	495		527.5	y	505		528. 5		521.5	515
Temperature difference, ΔT , ${}^{O}C$	433 452		406. 5 486	*****	429 443		410.5 478		419.5 454	420 463
Radiator temperature (meas), T _R , ^O C Voltage, V	0. 1773	0. 1605	0. 1564	0, 1739	0. 1743	0. 1728	0. 1595	0. 1355	0. 1661	403
								1	1	
Run 21-3; curre	1	A; total		Γ		I	Τ	1	T	₆ =
Hot junction temperature (calc), T _{HJ} , OC	930		922		934		928		933	929
Cold junction temperature (meas), T_{CJ} , ^{o}C	505		538		514 420		538		532	525 404
Temperature difference, ΔT, ^O C Radiator temperature (meas), T _R , ^O C	425 460		384 494	******	451		390 488		401	471
Voltage, V	0. 1249	0. 1041	0. 1021	0. 1192	0. 1221	0, 1180	0. 1054	0.0790	0, 1110	
				L			L	0.070-	0,1110	l
Run 21-4; curre	Г	A; totai	1		Τ	Γ	Г	Τ		Ι
Hot junction temperature (calc), T _{HJ} , OC	945		898		946		912		921	924
Cold junction temperature (meas), T _{CJ} , OC	512.5		546		523		544		540	533
Femperature difference, ΔT, ^O C Radiator temperature (meas), T _p , ^O C	432.5 467		352 503		423 459		368 494		381 470	491
Voltage, V	0,0720	0.0467	0.0476	0.0632	0.0686	0.0616	0, 0520	0.0230	0.0557	
Run 21-5; cu		I	l			L			I	L
	Ι	, total ve	T	1	,	1	0.10	T	nce	0.15
Hot junction temperature (calc), T _{HJ} , ^o C Cold junction temperature (meas), T _{CJ} , ^o C	841 444		840 470		853 458		848 471		855 465	847 462
Temperature difference, ΔT , ${}^{0}C$	397		370		395		377		390	385
Radiator temperature (meas), T _R , ^o C	411		440		407		432		416	421
Voltage, V	0. 2249	0.2166	0. 2095	3, 2265	0. 2232	0. 2238	0, 2136	0. 1984	0. 2210	
Run 21-6; curre	ent. 1.33	2 A: tota	l voltage.	1, 503 V	; total po	ower, 2.0	1		L	L
Hot junction temperature (calc), T _{HJ} , ^O C	834		842		846	T	854		848	845
Cold junction temperature (meas), T_{CJ} , ${}^{o}C$	453		481		467		488		474	473
Temperature difference, ΔT , $^{\circ}C$	381		361		379		366		374	372
Radiator temperature (meas), T _R , ^o C	420		449		416		441		424	430
Voltage, V	0. 1749	0. 1623	0. 1572	0.1736	0.1726	0. 1704	0, 1614	0. 1442	0. 1686	
Run 21-7; curre	ent, 2.74	A; total	voltage,	1.005 V;	total pov	ver, 2.76	5 W			
Hot junction temperature (calc), T _{HJ} , ^o C	835		834		845		839		843	839
Cold junction temperature (meas), T _{CJ} , OC	463		493		477		492		486	482
Temperature difference, ΔT, OC	372		341		368		347		357	357
Radiator temperature (meas), T _R , ^o C	428	0.1054	458	0.1170	425 0.1197	0.1150	452 0, 1065	0.0963	435 0. 1124	439
Voltage, V	0. 1221	L	0, 1027	1		L		0.0863	0. 1124	
Run 21-8; curre	ent, 4.09	A; total	voltage,	0, 5012 V	; total pe	1)5 W	_	1	
Hot junction temperature (calc), T _{HJ} , ^O C	846		815		853		823		835	834
Cold junction temperature (meas), T _{CJ} , °C	474		505		488		503		498	494
Temperature difference, ΔT, °C	372		310		365		320		337	340
Radiator temperature (meas), TR, °C	438	0.0101	468	0.0070	432	0.0500	461	0.0000	443	448
Voltage, V	0.0690	0.0481	0.0479	0.0618	0.0665	0.0590	0.0510	0.0289	0.0565	

Parameter			1		Hot sho	e number				Aver
	32	52	17	45	31	48	38	46	49	age
Run 21-9;	current,	0; total	voltage,	1.657 V;	total pow	er, 0				
Hot junction temperature (calc), T _{HJ} , ^O C	737		737		751		745		749.5	744
Cold junction temperature (meas), T _{CJ} , ^o C	408		430		422		432		423.5	423
Temperature difference, ΔT, °C	329		307		329		313		326	321
Radiator temperature (meas), T _R , ^o C	378 0. 1874	0 1000	404	0.1000	377 0, 1879	0.1050	398	0.1000	383	389
Voltage, V		0. 1833	0. 1750	0. 1889		0. 1856	0, 1780	0. 1680	0. 1862	
Run 21-10; curr	[6 A; tota	l voltage,	1. 232 V	; total po	ower, 1.5	55 W			
Hot junction temperature (calc), T _{HJ} , OC	730		738		744		742		742	739
Cold junction temperature (meas), T _{CJ} , o _C	416		442		431		441.5		431.5	433
Temperature difference, ΔT , ${}^{O}C$	314		296		313		300.5		310.5	306
Radiator temperature (meas), T _R , ^o C	388	0 1880	416	0.1410	388	0 1000	410	0 1100	390	398
Voltage, V	0, 1420	0. 1329	0. 1260	0. 1412	0. 1413	0. 1369	0, 1299	0. 1189	0. 1390	
Run 21-11; curi	rent, 1.9	1 A; tota	l voltage,	1.009 V	; total po	wer, 1.9	92 W			
Hot junction temperature (calc), T _{HJ} , ^O C	729		731		743		738		739	736
Cold junction temperature (meas), T _{CJ} , ^o C	420. 5		445		435		446		436	437
Temperature difference, ΔT, ^o C	308.5		286		308		292		303	299
Radiator temperature (meas), T _R , ^o C	392		419		392		413		396	402
Voltage, V	0.1185	0. 1079	0. 1019	0. 1166	0.1181	0. 1124	0. 1060	0.0939	0. 1143	
Run 21-12; curr	rent, 3.2	3 A; tota	l voltage,	0.550 V	; total po	ower, 1.7	'8 W			
Hot junction temperature (calc), T _{HJ} , ^O C	732		715		744		725		734	730
Cold junction temperature (meas), T _{CJ} , °C	430		455, 5		444		456.5		448	447
Temperature difference, ΔT, ^O C	302		259.5		300		268. 5		286	283
Radiator temperature (meas), T _R , ^o C	401		428		401		422		407	412
Voltage, V	0.0704	0.0559	0, 0521	0.0652	0.0693	0.0619	0, 0555	0.0410	0,0629	
Run 21-13;	current,	0; total	i voltage,	1. 329 V	; total po	wer, 0				
Hot junction temperature (calc), T _{HJ} , ^O C	633		633		650		642.5		647	641
Cold junction temperature (meas), ${}^{113}_{CJ}$, ${}^{0}_{C}$	370		389		386		394.5		384	385
Temperature difference, ΔT , ${}^{o}C$	263		244		264		248		263	256
Radiator temperature (meas), T _R , ^o C	345		371		347		365		350	355
Voltage, V	0. 1503	0. 1486	0. 1395	0. 1514	0.1508	0. 1448	0. 1418	0. 1359	0. 1506	
Run 21-14; cur	ent, 1.0	37 A; tot:	al voltage	, 1.002	V; total p	ower, 1.	04 W	k		
Hot junction temperature (calc), T _{HJ} , ^o C	630		640		646		644		642	640
Cold junction temperature (meas), T_{CJ} , ${}^{o}C$	375		402, 5		392		401		389	392
Temperature difference, ΔT , ${}^{O}C$	255		237. 5		254		243		253	248
Radiator temperature (meas), T _R , ^O C	350		379		351		370		354	361
Voltage, V	0.1165	0.1110	0. 1013	0. 1141	0. 1161	0. 1087	0. 1060	0.0993	0.1152	
Run 21-15; cur	rent, 2.2	4 A; tota	ı l voltage,	0.612 V	; total po	wer, 1.3	87 W	L	1	L
Hot junction temperature (calc), T _{HJ} , ^o C	629		625		644		633		636	633
Cold junction temperature (meas), T_{CJ} , ${}^{o}C$	383		408		400		410		396	399
Temperature difference, ΔT , ${}^{O}C$	246		217		244		223		240	234
Radiator temperature (meas), T _R , ^o C	359		381		360		377		360	367
Voltage, V	0.0752	0.0660	0.0589	0.0706	0.0742	0.0658	0,0622	0.0543	0.0720	
Run 21-16; cur	ent, 3.0	3 A; tota	l voltage,	0.3571	V; total p	ower, 1.	08 W		4	L
Hot junction temperature (calc), T _{HJ} , ^o C	635		611		650		624		637	631
Cold junction temperature (meas), T_{CJ} , ${}^{o}C$	389		413		405		416		402.5	405
		l					208			226
Temperature difference, AT, OC	246		198		245		200		234.5	200
Temperature difference, ΔT, ^O C Radiator temperature (meas), T _R , ^O C	246 366		392		364		382		367	375

Parameter		***************************************			Hot shoe	e number				Aver-
	50	59	28	58	26	61	27	23	30	age
Run 2-1; c	urrent, 4	.78 A; to	otal volta	ge, 0.51	22 A; tota	al power,	2. 45 W	1	l	L
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	889 527 362 0.0498	0. 0393	942 523 419 0.0655	0.0657	932 534 398 0.0590	0,0596	912 535 377 0.0529	0.0377	946 513 433 0.0698	924 526 398
Run 2-2; curren	it, 3.46 A	A; total v	oltage, 1	.006 V;	total pow	er, 3.48	W	Т	Γ	Ι
Hot junction temperature (calc), T _{HJ} , ^O C Cold junction temperature (meas), T _{CJ} , ^O C Temperature difference, ΔT, ^O C Voltage, V	914 514 400 0.1072	0. 0944	928 511 417 0. 1164	0. 1218	929 519 410 0. 1123	0. 1174	922 522 400 0. 1073	0.0903	928 500 428 0. 1226	924 513 411
Run 2-3; curren	<u> </u>	total vo	Γ	509 V; 10	l	1, 3.100	1	T	T	I
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	924 500 424 0. 1660	0. 1509	928 500 428 0, 1690	0. 1788	931 507 424 0. 1660	0. 1766	930 509 421 0. 1633	0. 1440	929 491 438 0. 1769	928 501 427
Run 2-4; currer	it, 0; tot	al voltage	e, 2.24 V	; total po	ower, 0					
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	934 486 448 0. 2511	0. 2329	924 487 437 0. 2453	0. 2617	928 492 436 0. 2443	0. 2630	932 495 437 0, 2449	0. 2220	935 476 459 0. 2565	931 487 444
Run 2-5; currer	it, 4.3 A	; total vo	Itage, 0.	494 V; to	otal powe	r, 2.12 V	V			
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	809 486 323 0.0490	0. 0399	845 487 358 0.0599	0,0619	846 493 353 0, 0585	0.0584	825 495 330 0.0511	0. 0392	847 477 370 0.0640	834 488 346
Run 2-6; curren	t, 2.87 A	; total v	oltage, 1	. 009 V; t	otal powe	er, 2.89	W			
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	830 473 357 0. 1088	0. 0972	838 474 364 0. 1129	0. 1203	843 478 365 0. 1137	0. 1190	838 482 356 0, 1080	0. 0942	838 464 374 0.1195	837 474 363
Run 2-7; curre	nt, 1.42	A; total v	oltage, 1	. 513 V;	total pow	er, 2.15	W			
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	841 463 378 0, 1673	0. 1537	841 465 376 0. 1657	0. 1770	844 466 378 0. 1676	0. 1785	844 470 374 0. 1642	0. 1475	839 453 386 0, 1746	842 463 379
Run 2-8; c	urrent,); total v	oltage, 2	. 011 V;	total powe	er, 0	7	T	1	
Hot junction temperature (calc), T_{HJ} , ^{0}C Cold junction temperature (meas), T_{CJ} , ^{0}C Temperature difference, ΔT , ^{0}C Voltage, V	851 453 398 0. 2256	0. 2095	843 459 384 0, 2173	0, 2340	848 458 390 0. 2209	0, 2370	848 461 387 0, 2199	0. 2004	850 446 404 0. 2290	848 455 393

Parameter				harmon and the second s	Hot sho	e number				Aver-	
	50	59	28	58	26 .	61	27	23	30	age	
Run 2-9; curre	nt, 3.51.	A; total v	oltage, (). 5272 V;	total pov	ver, 1.8	5 W	I			
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), $^{T}C_{J}$, ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	730 443 287 0, 0564	0.0483	747 450 297 0. 0603	0.0647	755 446 309 0.0654	0.0640	740 457 283 0, 0549	0.0440	743 458 285 0.0558	743 451 292	
Run 2-10; curre	ent, 2.09	A; total	voltage,	1. 031 V;	total pov	ver, 2.15	5 W	1	Τ		
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	745 432 313 0, 1139	0. 1039	751 441 310 0, 1120	0, 1220	755 435 320 0.1187	0, 1229	752 443 309 0. 1110	0, 0978	755 443 312 0. 1135	752 439 313 	
Run 2-11; curre	ent, 0.70	2 A; tota	l voltage	, 1.489 V	; total po	ower, 1.0)4 W	,	•		
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	751 422 329 0. 1666	0, 1546	756 434 322 0. 1597	0. 1739	756 427 329 0. 1666	0. 1766	757 432 325 0. 1621	0. 1469	757 429 328 0. 1654	755 429 326	
Run 2-12; current, 0; total voltage, 1.718 V; total power, 0											
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	757 418 339 0. 1933	0, 1799	751 429 32 2 0. 1834	0. 1999	758 423 335 0. 1910	0. 2035	758 428 330 0. 1880	0. 1710	758 423 335 0. 1911	756 424 332	
Run 2-14; curre	ent, 3.05	A; total	voltage,	0. 4070 V	; total po	ower, 1.2	24 W	3011,300	1000		
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	625 399 226 0.0423	 0, 0365	639 412 227 0.0429	0. 0495	654 404 250 0.0518	0.0487	634 408 226 0.0424	0.0359	638 406 232 0.0449	638 406 232	
Run 2-15; curre	ent, 2.01	A; total	voltage,	0. 7421 V	; total po	ower, 1.4	19 W				
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	633 390 243 0.0807	0.0737	642 403 239 0. 0780	0. 0874	646 393 253 0. 0874	0.0880	639 398 241 0.0793	0.0716	641 395 246 0, 0825	640 396 244 	
Run 2-16; curre	ent, 1.17	A; total	voltage,	1.005 V;	total pov	ver, 1.17	75 W				
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	639 384 255 0. 1114	0, 1030	644 397 247 0. 1053	 0, 1174	645 386 259 0. 1153	0. 1190	642 391 251 0. 1087	0. 0994	643 388 255 0. 1114	643 389 254 	
Run 2-17;	current,	0; total	voltage,	1. 363 V;	total pow	er, 0				10000	
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	646 378 268 0. 1532	0. 1427	643 393 250 0, 1430	0. 1580	647 379 268 0. 1533	0, 1612	645 385 260 0. 1485	0. 1370	645 381 264 0. 1508	645 383 262	

Test Section 3

Parameter					Hot shoe	e number		ALANG-ACTION HOLD	·	Aver-
	51	54	29	60	43	64	44	62	42	age
Run 5-5; c	urrent, C	; total v	oltage, 2.	239 V; t	otal powe	er, 0				
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	960 530 430 0. 2410	0. 2335	941 515 426 0. 2383	0. 2546	966 529 437 0. 2444	0. 2653	939 505 434 0. 2430	0. 2409	953 490 463 0. 2593	952 514 438
	954		944		956		935		939	946
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	540 414 0. 1591	0. 1480	529 415 0, 1603	0. 1701	539 417 0. 1620	0, 1801	515 420 0, 1638	0. 1584	500 439 0. 1794	525 421
Run 5-7; curre	nt, 3.29 A	A; total v	oltage, 1	. 006 V; 1	otal pow	er, 3.31	w			
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	943 547 396 0, 1049	0. 0907	939 536 403 0. 1086	0, 1138	946 546 400 0. 1073	0, 1240	929 522 407 0.1111	0. 1033	941 508 433 0. 1257	940 532 408
Run 5-8; curre	nt, 4.49	A; total v	oltage, 0	. 5294 V;	total pov	ver, 2.37	W			
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	922 552 370 0.0530	0, 0359	932 543 389 0.0584	0.0598	932 554 378 0. 0551	0.0694	924 530 394 0.0600	0, 0506	953 516 437 0.0737	933 539 394
Run 7-3; curre	nt, 4, 22	A; total v	oltage, 0	. 4780 V;	total pov	ver, 2.02	W			
Hot junction temperature (calc), T_{HJ} , ^{o}C Cold junction temperature (meas), T_{CJ} , ^{o}C Temperature difference, ΔT , ^{o}C Voltage, V	845 504 341 0, 0510	0. 0335	852 498 354 0. 0550	0. 0540	854 510 344 0.0520	0.0613	838 494 344 0. 0519	0, 0447	858 481 377 0.0625	849 497 352
Run 7-4; curre	nt, 2.81	A; total v	oltage, 1	.007 V;	total pow	er, 2.82	w	1	L	
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	854 490 364 0. 1099	0. 0945	849 484 365 0. 1108	0. 1142	861 496 365 0. 1103	0. 1216	844 483 361 0. 1084	0. 1035	849 470 379 0. 1195	851 485 366
Run 7-5; curre	nt, 1.46	A; total v	oltage, 1	. 502 V;	total pow	er, 2.19	w			
Hot junction temperature (calc), T_{HJ} , ^{O}C Cold junction temperature (meas), T_{CJ} , ^{O}C Temperature difference, ΔT , ^{O}C Voltage, V	858 477 381 0. 1650	0. 1516	851 473 378 0. 1624	0. 1706	865 484 381 0. 1647	0. 1778	848 471 377 0. 1617	0. 1586	848 458 390 0. 1729	854 473 381
Run 7-6; c	current, (); total v	oltage, 2	041 V; t	otal powe	er, 0				
Hot junction temperature (calc), T_{HJ} , ^{o}C Cold junction temperature (meas), T_{CJ} , ^{o}C Temperature difference, ΔT , ^{o}C Voltage, V	865 468 397 0, 2251	0. 2135	850 463 387 0, 2193	0. 2322	872 475 397 0. 2246	0. 2395	849 462 387 0. 2197	0.2186	859 450 409 0. 2317	859 464 395

Parameter					Hot sho	e number				Aver-
	51	54	29	60	43	64	44	62	42	age
Run 8-4; curren	nt, 3.53	A; total v	oltage, (). 460 V; t	otal pow	er, 1.62	W	I	1	L
Hot junction temperature (calc), T _{HJ} , ^O C	735		740		753		730		744	740
Cold junction temperature (meas), T _{CJ} , ^o C	452		450		463		454		436	451
Temperature difference, ΔT, °C	283		290		290		276		208	289
Voltage, V	0.0495	0.0369	0.0522	0.0530	0.0518	0.0526	0.0472	0.0462	0.0586	
Run 8-5; curren	nt, 1.989	A; total	voltage,	1.006 V;	total pov	ver, 1.99	w		1	
Hot junction temperature (calc), T _{HJ} , ^o C	739		738	744						
Cold junction temperature (meas), T _{CJ} , ^o C	437		434		451		440		422	437
Temperature difference, ΔT, ^O C	307		305		307		299		316	307
Voltage, V	0. 1112	0. 1001	0. 1099	0, 1153	0. 1111	0. 1113	0. 1057	0. 1069	0. 1177	
Run 8-6; currer	it, 0.687	A; total	voltage,	1. 452 V;	total pov	ver, 1.00	w			
Hot junction temperature (calc), T _{HJ} , ^o C	749		743		763		746		739	748
Cold junction temperature (meas), ${}^{10}_{CJ}$, ${}^{0}_{C}$ Temperature difference, ${}^{\Delta}T$, ${}^{0}C$	428		426		442		432		413	428
Temperature difference, ΔT , ${}^{O}C$	321		317		321		314		326	320
Voltage, V	0. 1605	0. 1514	0. 1567	0. 1663	0. 1606	0. 1630	0. 1535	0. 1567	0. 1661	
Run 8-7; c	urrent, (); total v	oltage, 1	.689 V; t	otal powe	er, 0				
Hot junction temperature (calc), T _{HJ} , ^o C	751		739		763		740		744	747
Cold junction temperature (meas), T _{CJ} , °C	423		421		436		425		408	423
Temperature difference, ΔT, ^O C	328		318		327		315		336	324
Voltage, V	0. 1869	0, 1787	0, 1811	0. 1931	0. 1866	0. 1902	0. 1792	0. 1829	0. 1918	
Run 8-8; curren	nt, 3.08	A; total v	oltage, 0	. 3692 V;	total pov	ver, 1.13	8 W	J	1	1
Hot junction temperature (calc), T _{HJ} , ^O C	640		642		658		631		643	643
Cold junction temperature (meas), T _{C.J} , O _C	406		405		421		411		391	407
Temperature difference, ΔT , ${}^{o}C$	234		237		237		220		252	236
Voltage, V	0.0409	0.0316	0.0421	0.0432	0.0419	0.0353	0, 0363	0.0390	0.0477	
Run 8-9; currer	nt, 1.94	A; total v	oltage, 0). 758 V; t	otal pow	er, 1.47	W			
Hot junction temperature (calc), T _{H.I} , ^o C	646		645		664		643		641	648
Hot junction temperature (calc), ${ m T_{HJ}}$, ${ m ^{O}C}$ Cold junction temperature (meas), ${ m T_{CJ}}$, ${ m ^{O}C}$	397		398		413		403		384	399
Temperature difference, ΔT, °C	249		247		251		240		257	249
Voltage, V	0.0840	0.0759	0.0823	0,0869	0.0848	0.0793	0.0780	0.0819	0.0894	
Run 8-10;	current,	0; total	voltage,	1. 380 V;	total pov	wer, 0		'		1
Hot junction temperature (calc), T _{HJ} , ^o C	651		642		666		641		645	649
Cold junction temperature (meas), T _{CJ} , OC	383		385		398		388		371	385
Temperature difference, ΔT , ${}^{o}C$	268		257		268		253		274	264

APPENDIX B

RCA LIFE-TESTING OF SOLAR THERMOELECTRIC PROTOTYPE TEST SECTION

Under contract NAS3-12443, an uncoated solar panel test section, fabricated under contract NAS3-10600, was life-tested at RCA, Harrison, New Jersey, for 5500 hours at reference design conditions with fixed input power. The test section was identical to those described in the main body of this report except for the following:

- (1) The thermocouple mount studs were steel rather than beryllium.
- (2) The radiator plate was aluminum rather than beryllium.
- (3) The radiator surface was coated with aquadag rather than calcium titanate.

For this test section, the design power of 2.81 watts at 1 volt was again achieved at the design temperature difference of 361° C; however, the required increase in hot and cold junction temperatures relative to reference design values was 40° C rather than 50° C.

The results of the life-testing are shown in figure 8 for a calculated average hot junction temperature of 830°C. During this test, the external load was periodically adjusted to maintain a load-resistance-to-internal-resistance ratio of approximately 1.2. After the first 1500 hours, the power degraded from 2.81 to 2.63 watts, or 6.6 percent, while an additional 1 percent degradation occurred between 1500 and 5500 hours.

The internal resistance $\,R_{i}^{}\,$ of the nine-thermocouple module was determined using the relation:

$$-R_{i} = \frac{V_{OC}^{i} - V_{L}}{I} \tag{B1}$$

where

V_I, load voltage

V'OC instantaneous open-circuit voltage

I current

The ''instantaneous' open-circuit voltage is usually measured within 1 second after opening the circuit. As shown in figure 8, the internal resistance of the panel increased from 300 milliohms to about 353 milliohms after 5500 hours of testing. This increase in resistance, about 18 percent, is attributed to precipitation of phosphorus dopant in the n-type Si-Ge which is a function of both time and temperature (ref. 5)

At the conclusion of the 5500 hour life-test, the test section was disassembled and one of the nine Si-Ge thermocouples was metallographically examined. No change in appearance was observed relative to the as-fabricated thermocouples. The remaining eight thermocouples were inspected for total resistance, element resistance, and bond-contact resistance. A comparison of the room-temperature resistance for the couples as fabricated and after 5500 hours is shown in table II. Here it can be seen that the increase in couple resistance after 5500 hours is due almost entirely to increased resistance in the n-type Si-Ge.

The apparent discrepancy between the increase in resistance at operating temperature, about 18 percent, and at room temperature, about 50 percent, after 5500 hours is due to the relatively slow module cool-down rate, typically about 2 hours from reference operating temperatures to room temperature. During this time, additional precipitation of phosphorus occurs due to the decreasing solubility of phosphorus in Si-Ge with decreasing temperature, and hence, causes a substantial increase in room temperature resistance. This effect is reversible, and subsequent heating of the test section to higher temperatures would allow the precipitated phosphorus to go back into solid solution with the Si-Ge.

REFERENCES

- 1. Bifano, W. J.; and Scudder, L. R.: Comparison of Solar Direct-Energy Conversion Systems Operating Between 1.0 and 0.1 Astronomical Unit. NASA TN D-3788, 1967.
- 2. Raag, V.; Berlin, R. E.; and Gnau, L. H.: Solar Thermoelectric Generator Design and Panel Development Program. Rept. No. 647DR-1220 Radio Corporation of America (NASA CR-72340), 1967.
- 3. Gnau, L. H.: Solar Thermoelectric Generator Design and Panel Development Program Fabrication Report, Rept. No. 647FR-32068, Radio Corporation of America, (NASA CR-72386), 1968.
- 4. Anon.: Silicon Germanium Thermoelectric Materials and Module Development Program, 5 Quarterly Report. Rept. No. ALO (2510)-5, Radio Corporation of America, Jan. 1, 1969 to March 31, 1969.
- 5. Anon.: Silicon Germanium Thermoelectric Materials and Module Development Program, Topical Report. Rept. No. ALO (2510)-T1, Radio Corp. of America, Jan. 1, 1968 to November 1, 1969.

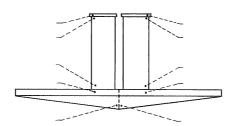
TABLE I. - JUNCTION TEMPERATURES REQUIRED TO ACHIEVE

REFERENCE DESIGN POWER AT 1 VOLT

	Reference design	Panel 1	Panel 2	Panel 3
Hot junction tempera- ture, T _{HJ} , ^O C	791	a ₈₃₉	^a 837	^a 851
Cold junction tempera- ture, T _{CJ} , ^o C	430	^b 482	^b 474	^b 485
Temperature difference, ΔT , ^{O}C	361	357	363	366
Power output, Po, W	2.81	2. 76	2. 89	2. 82
Voltage, V	1,000	1.005	1. 009	1, 007

^aCalculated, average of five of nine Si-Ge thermocouples.

TABLE II. - TEST PANEL THERMOCOUPLE RESISTANCE DATA SHEET



Module	Thermo-		As fabricated After 5574 hours																		
posi- tion	couple number		Resistance, mΩ													·					
		А-В	в-с	C-D	E-F	G-H	H-J	J-K	A-K	A-D	G-K	А-В	В-С	C-D	E-F	G-H	H-J	J-K	A-K	A-D	G-K
1	25	0.37	6.00	0.30	0. 16	0.40	4, 89	0. 33	12. 6	6.67	5. 62	0. 33	7. 13	0.92	0.32	0.35	7. 40	2.35	18, 40	7.38	10. 10
2	37	. 36	6.31	. 20	. 16	. 51	5. 30	. 39	13.4	6.87	6.20	. 31	6.53	. 96	. 23	. 46	7.83	3.71	20.50	7.80	12.00
4	39	. 46	6.37	. 19	. 15	. 23	5.34	. 34	13.3	7. 02	5.91	. 25	6.62	. 94	. 31	. 34	7.41	3. 15	19.80	7.81	10.90
5	35	. 32	6. 26	. 35	. 13	. 34	4.74	. 19	12.6	6. 93	5. 27	. 29	6.19	1.05	. 38	. 49	7.57	1. 44	17.80	7.53	9, 50
6	40	. 38	6. 55	. 15	. 18	. 32	5. 59	. 21	13.6	7. 08	6. 12	. 34	6.64	. 83	. 35	. 37	7. 90	4. 73	21.60	7.81	13.00
7	33	. 24	5. 96	. 33	. 20	. 45	4.61	. 15	12. 1	6. 53	5, 21	. 33	5. 96	. 92	. 32	. 38	6, 61	1. 96	17.50	7.21	8, 95
8	41	. 42	6.54	. 17	. 13	. 22	5.46	. 46	13.7	7. 13	6.12	. 26	6.79	. 87	. 28	. 41	7.55	3.84	20. 50	7.92	11, 80
9	34	. 36	6.05	. 37	. 11	. 39	4.75	. 19	12.4	6.78	5.33	. 31	6.18	1. 21	. 44	. 47	6. 53	1.98	17.60	7.70	8.98

b Measured, average of five of nine Si-Ge thermocouples.

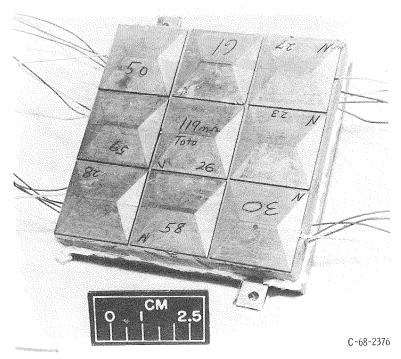


Figure 1. - Silicon-germanium solar thermoelectric test panel.

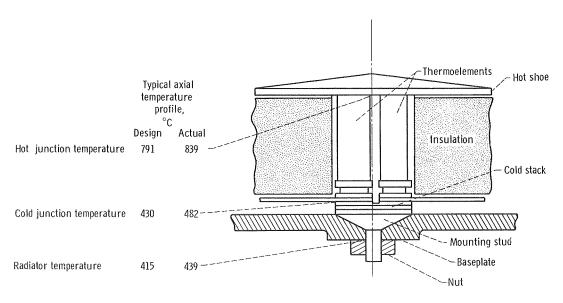


Figure 2. - Thermocouple assembly with typical axial temperature profile at reference design power.

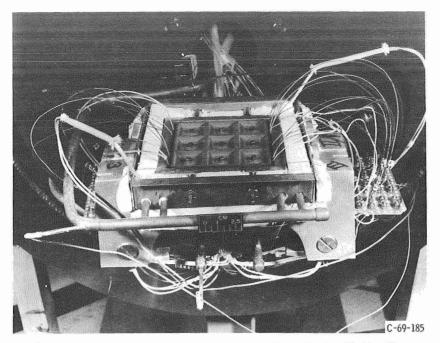


Figure 3. - Solar thermoelectric panel mounted in test fixture, showing ribbed beryllium radiator surface.

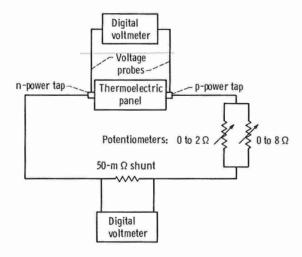


Figure 4. - Schematic of thermoelectric circuit.

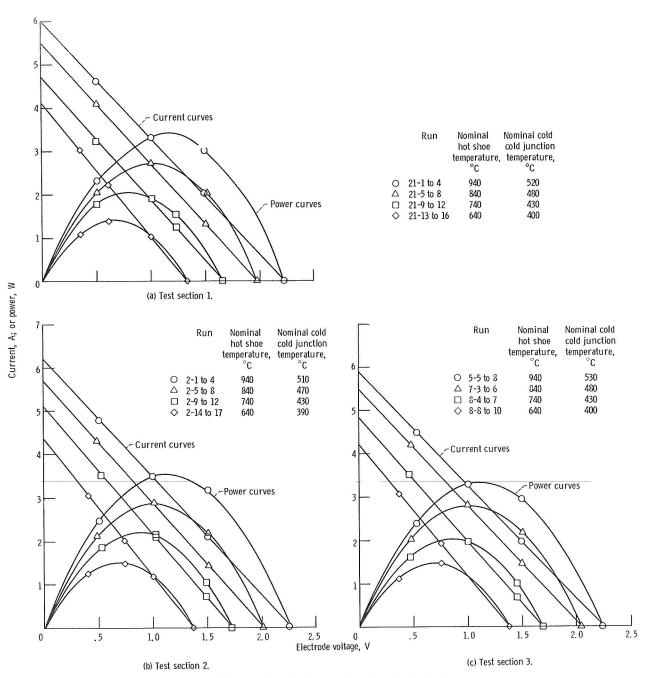


Figure 5. - Current and power as functions of electrode voltage.

NATIONAL AFRONAUTICS AND SPACE ADMINISTRATION

WASHINGTON, D. C. 20546

OFFICIAL BUSINESS



POSTMASTER: If Undeliverable (Section 158 Postal Manual) Do Not Return

'The aeronautical and space activities of the United States shall be conducted so as to contribute... to the expansion of human knowledge of phenomena in the atmosphere and space. The Administration shall provide for the widest practicable and appropriate dissemination of information concerning its activities and the results thereof."

-NATIONAL AERONAUTICS AND SPACE ACT OF 1958

NASA SCIENTIFIC AND TECHNICAL PUBLICATIONS

TECHNICAL REPORTS: Scientific and technical information considered important, complete, and a lasting contribution to existing knowledge.

TECHNICAL NOTES: Information less broad in scope but nevertheless of importance as a contribution to existing knowledge.

TECHNICAL MEMORANDUMS: Information receiving limited distribution because of preliminary data, security classification, or other reasons

CONTRACTOR REPORTS: Scientific and technical information generated under a NASA contract or grant and considered an important contribution to existing knowledge.

TECHNICAL TRANSLATIONS: Information published in a foreign language considered to merit NASA distribution in English.

SPECIAL PUBLICATIONS: Information derived from or of value to NASA activities. Publications include conference proceedings, monographs, data compilations, handbooks, sourcebooks, and special bibliographies.

TECHNOLOGY UTILIZATION
PUBLICATIONS: Information on technology used by NASA that may be of particular interest in commercial and other non-zerospace applications. Publications include Tech Briefs, Technology Utilization Reports and Technology Surveys.

Details on the availability of these publications may be obtained from:

SCIENTIFIC AND TECHNICAL INFORMATION OFFICE

NATIONAL AERONAUTICS AND SPACE ADMINISTRATION

Washington, D.C. 20546